

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s): Mehrdad Nikoonahad
Title: Optical System for Measuring Samples Using Short Wavelength Radiation
Application No.: 10/718,126 Filing Date: November 19, 2003
Examiner: Pham, Hoa Q. Group Art Unit: 2886
Docket No.: TNCR.197US1 Conf. No.: 9108

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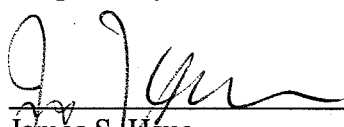
COMMENTS ON STATEMENT OF REASONS FOR ALLOWANCE

Dear Sir:

We disagree with the Examiner's statement of reasons for allowance as we feel the statement does not pertain to claims 125, 128 and 146.

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Respectfully submitted,


James S. Hsue
Reg. No. 29,545

March 18, 2008
Date

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